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**19. Analysis of communication circuits based on multidimensional Fourier transformation**

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## 1. High-frequency AC hot-carrier degradation in CMOS circuits

Vei-Han Chan; Kopley, T.E.; Marcoux, P.; Chung, J.E.;

Electron Devices Meeting, 1994. Technical Digest., International

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Fenouillet-Beranger, C.; Raynaud, C.; Faynot, O.; Grouillet, A.; Du Port de Pontcharra, J.; Tabone,

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Panov, Y.V.; Lee, F.C.;

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Volume 2, 3-7 March 1996 Page(s):685 - 691 vol.2

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Khachab, N.I.; Ismail, M.;

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Volume 38, Issue 12, Dec. 1991 Page(s):1439 - 1450

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## 3. Finite GB and MOS parasitic capacitance effects in a class of MOSFET-C filters

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